



PHASICS
the phase control company

SID4 UHR

ULTRA HIGH RESOLUTION WAVE FRONT SENSOR

SID4 UHR Ultra High Resolution wavefront sensor is adapted for optics metrology needs. It combines the SID4 ease of implementation with high sampling and resolution. Its large aperture allows to get a live wavefront measurement over the complete sample under test. The SID4 UHR is optimized for **surface inspection** (roughness, high frequency defects detection...) and **optical components characterization** (lens, objective, aspherical and freeform optics...).

Built with a high-performance camera it provides incredible precision for laser characterization. The 512 x 512 (option 666 x 666) phase map sampling with such compactness make the SID4 UHR a unique tool for optics and laser metrology in both research and industry fields.

KEY FEATURES



High Resolution
512 x 512



High Dynamic
range



Large analysis
pupil



Instantaneous measure
on large Field



Optimal signal
to noise ratio



Compactness for
easy implementation

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WAVEFRONT SENSOR

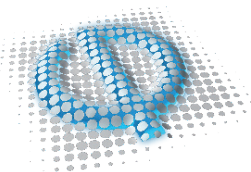
APPLICATIONS

- 1 Large aperture laser characterization
- 2 Optical components characterization
- 3 Surfaces inspection

SPECIFICATIONS

Wavelength range	400 - 1100 nm
Aperture dimension	15.16 x 15.16 mm ²
Spatial resolution	29.6 μm (option 22.2 μm)
Phase and intensity Sampling	512 x 512 (option 666 x 666)
Phase resolution	< 2 nm RMS
Frame rate	8 fps
Real-time processing frequency ⁽¹⁾	1 Hz (full resolution)
Interface	Giga Ethernet
Dimensions (W X H X L)	60 x 60 x 70 mm
Weight	~ 450 g

(1) Using the computer provided by PHASICS on SID4 Software



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